

Notice of References Cited	Application/Control No. 10/676,914		Applicant(s)/Patent Under Reexamination DANDALA ET AL.	
	Examiner Mark L. Berch		Art Unit 1624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,888,429 A	12-1989	Hebeisen, Paul	548/194
*	B	US-5,523,400 A	06-1996	Wei et al.	514/202
*	C	US-2003/0204082 A1	10-2003	Manca et al.	540/222
*	D	US-2004/0210049 A1	10-2004	Lee et al.	540/222
*	E	US-2004/0210049	10-2004	Lee et al.	540/222
	F	US-			
*	G	US-2004/0242556 A1	12-2004	Dandala et al.	514/202
*	H	US-6,878,827 B2	04-2005	Ono et al.	548/194
*	I	US-2005/0080255 A1	04-2005	Kumar et al.	540/222
*	J	US-2005/0137182 A1	06-2005	Dandala et al.	514/202
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q	JP 02000790 A2	01-1990	World Intellect	SAKANE et al	---
	R					
	S	WO 00/79211 A1	01-2001	World Intellect	KAMEYAMA, et al.	C07D501/22
	T	WO 2004016623 A1	02-2004	World Intellect	KREMMINGER et al.	C07D501/00

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Translation of WO 00/79211 A1
	V	Lin, Hecheng Huaxue 9(5) 383-385 2001 and translation
	W	Translation of JP 02000790 A2
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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